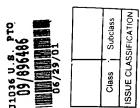
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U.S. **UTILITY** Patent Application

O.I.P.E. PATENT DATE			
	SCANNED A 4 QA.	PATENT DATE	
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 APPLICATION NO.
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APPLICANTS

TIFLE

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On-chip design-for-testing structure for CMG8 APS (active pixel sensor) image sensor

PTO-2040 12/99

ISSUING CLASSIFICATION							
ORIGIN	ORIGINAL CROSS REFERENCE(S)						
CLASS	CLASS SUBCLASS		SUBCLASS (ONE SUBCLASS PER BLOCK)				
INTERNATIONAL	L CLASSIFICATION						
			☐ Continued on Issue Slip Inside File Jacket				

TERMINAL	DRAWINGS			CLAIMS ALLOWED	
□ DISCLAIMER	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
The term of this patent subsequent to(date)				NOTICE OF ALI	LOWANCE MAILED
has been disclaimed.	(Assistant Examiner)		(Date)		
The term of this patent shall not extend beyond the expiration date					
of U.S Patent. No.				ISSUE FEE	
				Amount Due	Date Paid
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The terminalmonths of this patent have been disclaimed.				ISSUE BAT	CH NUMBER
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